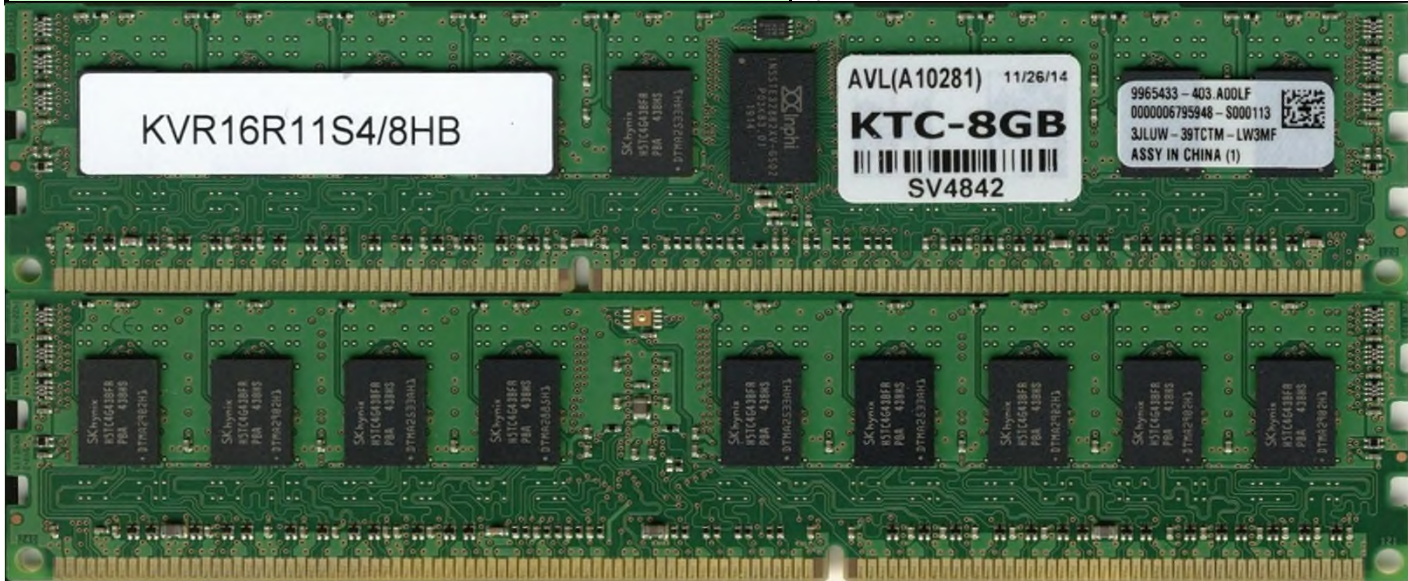


	AVL Supermicro server platform Memory Module Qualification Test		
	Intel X5650(WSM) x 2, Intel 5520 (Tylersburg), Rev B3	Test Results	Pass
	PN: KVR16R11S4/8HB (8GB / RDIMM / ECC) On: X8DT6-F Rev.1.3		

RP77D3x-128-KI-SQ-SMC-V2		Module Information		Rev 04/25/2013
AVL WorkOrder #	WD2716	AVL A#	10281	
Start Date	12/3/2014	End Date	12/5/2014	
Tested By	Van N.			
Module Manufacturer	Kingston			
Module Part Number	KVR16R11S4/8HB			
Module BOM Number	9965433-403.A00LF			
Module Capacity / Memory Type / ECC	8GB / RDIMM / ECC			
Module Configuration (Width, # of devices, # of Ranks)	1Gx72 /18 Devices / 1 Rank			
Module Speed (Data rate of Mbps, CL-tRP-tRCD)	DDR3-1600 /11-11-11			
DRAM Device Vendor	SK Hynix			
DRAM Device Part Number / Date code	H5TC4G43BFR-PBA		1438	
DRAM Die Revision / Process Technology (nm)	B			
DRAM Device Config (Density / Width)	4Gbit / x4 / 1024Mx4bit			
Thermal Sensor Device Vendor / Part Number / Revision	Atmel AT30TSE002B			
Register Device Vendor / Part Number / Revision	Inphi INSSTE32882XV-GS02		3.1	



Platform System Information				
Motherboard Info (Model# & MB Revision & MB S/N & AVL S/N)	X8DT6-F	1.3	VMAS59161	SK4375
BISO Revision / BIOS Date / MRC Rev.	2.0c	5/5/2012		
CPU / Speed	Intel X5650(WSM) x 2		2.66GHz	
Chipset info (Stepping)	Intel 5520 (Tylersburg), Rev B3			



AVL Supermicro server platform Memory Module Qualification Test

Intel X5650(WSM) x 2, Intel 5520 (Tylersburg), Rev B3

PN: KVR16R11S4/8HB (8GB / RDIMM / ECC) On: X8DT6-F Rev.1.3

Test Results:

PASS

Comments:

AVL Memory Module Qual Test Results Summary

Test # and name	Test Description	Specs	Test Results	Comments
1. Latest BIOS Upgrade & Configuration	Download / Upgrade latest BIOS & record size and speed detection	Per test platform, DIMM & config spec	Done	Record memory size & speed at each test only
2. SPD Check	Memory module SPD content check for JEDEC compliance	JEDEC	Pass	Use proprietary tools
3. Reset Cycle	Run Linux based diags & utility software @55°C	50 loops	Pass	1 DIMM Per Channel when applicable
4a. Stress Application Test	Run Linux based diags & utility software @55°C	8 Hour per config	Pass	DIMM Loading per spec
4b. Stream Benchmark Test		5 loop per config	Pass	DIMM Loading per spec
4b. Reset Cycle		200 loop per config	Pass	DIMM Loading per spec
5. Functional Stress Test	Memory Stress Test @55°C	12hrs	Pass	DIMM Loading per spec
6. Stress Application Test	Run Linux based diags & utility software @55°C	8hrs	N/A	3 DIMM Per Channel when applicable

Note: All test under IMC Vdd=Nom, Vref=Vddnom/2